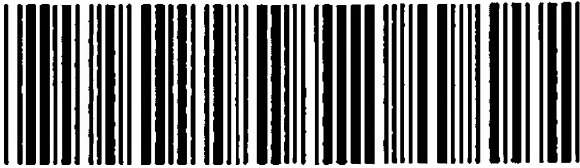


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/807,364	LAI, HAN-CHUNG	
	Examiner	Art Unit	
	Mike Qi	2871	

SEARCHED			
Class	Subclass	Date	Examiner
349	54;46	3/15/2006	ZQQ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East search; US-PGPUB;USPAT;USOCR; EPO;JPO:DERWENT;IBM_TDB; update search (see search history printout)	3/15/2006	